Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
40/000 207	A 3110 A1A/A ET A1

AZUSAWA ET AL.

10/698,367 Examiner

Art Unit

Nhan T. Tran

2622

	SEARCHED				
Class	Subclass	Date	Examiner		
348	208.8	5/1/2007	NT		
396	55	5/1/2007	NT		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
•				
	search - see ory printout	5/2/2007	NT	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	5/2/2007	NT		
348/208.1-208.16 (text search - see search history printout)	5/2/2007	NT		
396/52-55 (text search - see search history printout)	5/2/2007	NT		
Inventorship search - see search history printout	5/2/2007	NT		
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